

AMENDMENTS TO THE CLAIMS

In accordance with Rule 1.121, a complete claim listing is presented below, including appropriate status identifiers. Changes in the amended claims are shown by strikethrough for deleted material, and by underlining for added material.

1-47. (Cancelled).

48. (Currently Amended) A method for contact printing comprising:
patterning a first ink on a ~~flat~~ surface of a scanning probe microscopy probe to form ~~an~~ a first ink pattern on the ~~flat~~ surface; and
positioning the ~~flat~~ surface near a first substrate, wherein the first ink pattern is transferred from the ~~flat~~ surface to the first substrate.

49. (Currently Amended) The method of claim 48, wherein the first ink pattern is transferred from the ~~flat~~ surface to the substrate a plurality of times.

50. (Currently Amended) The method of claim 48 further comprising positioning the ~~flat~~ surface near a second substrate, wherein the first ink pattern is transferred from the ~~flat~~ surface to the second substrate.

51. (Currently Amended) The method of claim 48 further comprising patterning a second ink on the ~~flat~~ surface to form a second ink pattern on the surface.

52. (Previously presented) The method of claim 51, wherein the first ink and the second ink comprise the same material.

53. (Currently Amended) The method of claim 48, wherein the first ink pattern comprises more than one pixel.

54. (New) The method of claim 53, wherein the first ink pattern comprises more than two pixels.

55. (New) The method of claim 53, wherein the pixels do not come into contact with each other.
56. (New) The method of claim 51, wherein the second ink pattern comprises more than one pixel.
57. (New) The method of claim 56, wherein the second ink pattern comprises more than two pixels.
58. (New) The method of claim 51, wherein the first and second ink patterns are transferred from the surface to the first substrate.
59. (New) The method of claim 48 further comprising mounting the probe to a scanning probe microscope.
60. (New) The method of claim 59 where the patterning the first ink on the surface of the probe is performed before mounting the probe.
61. (New) The method of claim 59 where the patterning the first ink on the surface of the probe is performed after mounting the probe.